

BUREAU OF INDIAN STANDARDS

DRAFT FOR COMMENTS ONLY

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मसौदा भारतीय मानक
विद्युत का मापन माइक्रोवेव ट्यूब के गुण –
भाग 6: लो-पावर ऑसिलेटर क्लाइस्ट्रॉन
(पहला पुनरीक्षण)

Draft Indian Standard
Measurement of the Electrical
Properties of Microwave Tubes –
Part 6: Low-Power Oscillator Klystrons
(First Revision)

ICS No. : 31.100

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LITD 04: Electronic Display Devices and
systems Sectional Committee

Last Date for Comments: 07 July 2024

NATIONAL FOREWORD

(Formal clauses will be added later)

This Draft Indian Standard (Part 6) (First Revision) which is identical to IEC 60235-5:1972 'Measurement of the electrical properties of microwave tubes - Part 5: Low-power oscillator klystrons' issued by the International Electrotechnical Commission (IEC) *will be* adopted by the Bureau of Indian Standards on the recommendation of the Electronic Display Devices and systems Sectional Committee and approval of the Electronics and Information Technology Division Council.

This standard was originally published in 1981 and assistance has been derived from the IEC Pub 235-5:1972. The first revision aligns this Indian Standard with IEC 60235-5:1972, there is a need to align the formatting and appearance of the standard as per the current practice.

The following changes have been required in the standards under this revision:

- a) Adding Front cover page.
- b) Addition of Hindi Title.
- c) National foreword to be written as current practice.
- d) UDC Number to be changed to ICS code.

Measurement of the electrical properties of microwave tubes are being covered in a series of standards consisting of the following individual parts:

- Part 4: Magnetrons
- Part 6: Low - Power Oscillator Klystrons
- Part 7: High - Power Klystrons
- Part 8: Gas - Filled Microwave Switching Devices
- Part 9: Crossed - Field Amplifier Tubes
- Part 10: Crossed - Field Amplifier Tubes
- Part 11: General Measurements

The text of IEC Standard *may be* approved as suitable for publication as an Indian Standard without deviations. Certain terminologies and conventions are, however, not identical to those used in Indian Standards. Attention is particularly drawn to the following:

- a) Wherever the words 'International Standard' appear referring to this standard, they should be read as 'Indian Standard'
- b) Comma (,) has been used as a decimal marker, while in Indian Standards, the current practice is to use a point (.) as the decimal marker.

For the purpose of deciding whether a particular requirement of this standard is complied with, the final value, observed or calculated, expressing the result of a test or analysis, shall be rounded off in accordance with IS 2 : 2022 'Rules for rounding off numerical values (second revision)'. The number of significant places retained in the rounded off value should be the same as that of the specified value in this standard.

Note: The technical content of this document has not been enclosed as these are identical with the corresponding IEC Standard. For details please refer IEC 60235-5:1972 or kindly contact.

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